Burn-in testing is used to detect early failures in a population of electronic products. It usually requires the electrical testing of a product, using an expected operating electrical cycle over a specified period. Thermal or environmental stress screening can also be used. A manufacturer of automated test equipment (ATE) has selected Artesyn's iHP series intelligent, configurable high power system for its new burn-in test equipment range for semiconductor ICs, LEDs and touch panel displays. The wide range of outputs, flexibility, efficiency and built-in intelligence of the series made this an easy decision for the customer. The iHP series also meets the SEMI F47 voltage sag immunity standard, developed for the semiconductor industry and an important safety requirement in semiconductor processing equipment.